

115191

## SEARCH REQUEST FORM Scientific and Technical Information Center - EIC2800

Rev. 8/27/01 This is an experimental format -- Please give suggestions or comments to Jeff Harrison, CP4-9C18, 306-5429.

Date <u>2/24/04</u>	Serial # <u>101022,292</u>	Priority Application Date _____
Your Name <u>M. Lewis</u>	Examiner # _____	
AU <u>2800</u>	Phone <u>272-1838</u>	Room <u>5430</u>
In what format would you like your results? Paper is the default.		<input checked="" type="radio"/> PAPER <input type="radio"/> DISK <input type="radio"/> EMAIL

If submitting more than one search, please prioritize in order of need.

The EIC searcher normally will contact you before beginning a prior art search. If you would like to sit with a searcher for an interactive search, please notify one of the searchers.

02-25-04 A08:52 IN

Where have you searched so far on this case?

Circle: USPTO DWPI EPO Abs JPO Abs IBM TDB

Other: \_\_\_\_\_

What relevant art have you found so far? Please attach pertinent citations or  
Information Disclosure Statements. See DPC1 search 3/2/04

What types of references would you like? Please checkmark:

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Secondary Refs <input checked="" type="checkbox"/>	Foreign Patents _____	_____
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What is the topic, such as the novelty, motivation, utility, or other specific facets defining the desired focus of this search? Please include the concepts, synonyms, keywords, acronyms, registry numbers, definitions, structures, strategies, and anything else that helps to describe the topic. Please attach a copy of the abstract and pertinent claims.

Claims w/ 13-16, 19, 20, 25-26  
(Independent)

Problem: See paragraphs 3-10  
Solution: " " 11-13

Staff Use Only	Type of Search	Vendors
Searcher: <u>HORTON</u>	Structure (#) _____	STN _____
Searcher Phone: <u>2-2663</u>	Bibliographic <input checked="" type="checkbox"/>	Dialog <input checked="" type="checkbox"/>
Searcher Location: STIC-EIC2800, CP4-9C18	Litigation _____	Questel/Orbit _____
Date Searcher Picked Up: <u>2/27/04</u>	Fulltext _____	Lexis-Nexis _____
Date Completed: <u>3/03/04</u>	Patent Family _____	WWW/Internet _____
Searcher Prep/Rev Time: <u>550</u>	Other _____	Other _____
Online Time: <u>159</u>		

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S7	1201007	ALIGN???? OR (REL OR RELATI???????) (2N) (POSN OR POSITION- ???? OR ARRANG?????) OR LAYOUT OR SITD OR SITUAT?????
S9	1246	S1(3N)S2
S10	19651	S3(3N)S4
S11	1229	S5(5N)S6
S12	0	S9 AND S10 AND S11
S13	0	S1 AND S2 AND S3 AND S4 AND S5 AND S6
S14	30	S2 AND S3 AND S4 AND S5 AND S6
S15	23	RD (unique items)
S16	23	S15 NOT PY>2000
S17	90	S2 AND S3 AND S5 AND S6
S18	74	RD (unique items)
S19	69	S18 NOT PY>2000
S20	46	S19 NOT S16

20/9/3 (Item 3 from file: 2)

DIALOG(R) File 2:INSPEC

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5841578 INSPEC Abstract Number: A9807-0630M-002

Title: Strain gauge techniques for measuring thermal expansion

Author(s): Lord, J.D.

Issued by: Nat. Phys. Laboratory, Teddington, UK

Publication Date: May 1997 Country of Publication: UK 4 pp.

Material Identity Number: XR98-00056

Report Number: NPL CMMT(MN) 012

Abstract: A novel strain gauge technique has been used to measure the thermal expansion behaviour of a number of materials including **copper**, **aluminium** and both **polymer** and metal matrix composites.

**Copper** and **aluminium** were used for calibration purposes and validation of the technique. The values obtained from the strain gauge method for the coefficient of thermal expansion, between 25-100 degrees C, of **copper** and **aluminium** were 16.6 and  $23.4 \times 10^{-6}/\text{degrees C}$  respectively and these are in good agreement with typical handbook values. Two case studies are presented in this document, but a number of other materials are covered in an NPL report which describes the technique in more detail and discusses the merits and application of the strain gauge method. Practical tips are given where possible and conventional dilatometry data are presented for some materials for comparison. It is difficult to quantify the absolute accuracy of the measurements because this depends to a large extent on the quality of the strain gauge installation, but uncertainties associated with the measurements are typically 5-10%.